TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (Ultra High speed U-MOSIII)

TPCP8003-H

High Efficiency DC / DC Converter Applications
Notebook PC Applications
Portable Equipment Applications

- Small footprint due to a small and thin package
- High speed switching
- Small gate charge: QSW = 7.5 nC (typ.)
- Low drain-source ON-resistance: RDS (ON) = 130 m Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 5.4 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 100 \text{V)}$
- Enhancement mode: $V_{th} = 1.1 \text{ to } 2.3 \text{ V (VDS} = 10 \text{ V, ID} = 1 \text{mA})$

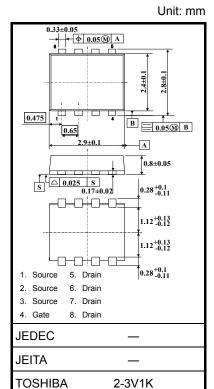
Absolute Maximum Ratings (Ta = 25°C)

| Characte | ristic | Symbol | Rating | Unit | |
|---|-------------------------------|------------------|------------|------|--|
| Drain-source voltage | | V_{DSS} | 100 | V | |
| Drain-gate voltage (R | $k_{GS} = 20 \text{ k}\Omega$ | V_{DGR} | 100 | V | |
| Gate-source voltage | | V_{GSS} | ±20 | V | |
| Drain current | DC (Note 1) | ΙD | 2.2 | Α | |
| Diam current | Pulsed (Note 1) | I_{DP} | 8.8 | , , | |
| Drain power dissipati | on $(t = 5 s)$ (Note 2a) | P_{D} | 1.68 | W | |
| Drain power dissipation $(t = 5 s)$ (Note 2b) | | P_{D} | 0.84 | W | |
| Single-pulse avalance | ne energy (Note 3) | E _{AS} | 3.93 | mJ | |
| Avalanche current | | I _{AR} | 2.2 | Α | |
| Repetitive avalanche | energy c=25°C) (Note 4) | E _{AR} | 0.016 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | -55 to 150 | °C | |

Note: For Notes 1 to 4, refer to the next page.

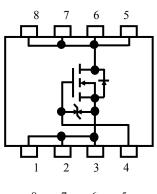
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

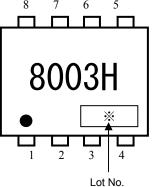
This transistor is an electrostatic-sensitive device. Handle with care.



Weight: 0.017 g (typ.)

Circuit Configuration





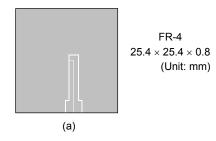
Thermal Characteristics

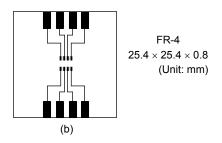
| Characteristic | Symbol | Max | Unit |
|--|------------------------|-------|------|
| Thermal resistance, channel to ambient $(t=5\;s) \eqno(Note\;2a)$ | R _{th (ch-a)} | 74.4 | °C/W |
| Thermal resistance, channel to ambient $(t=5\;\text{s}) \tag{Note 2b}$ | R _{th (ch-a)} | 148.8 | °C/W |

Note 1: The channel temperature should not exceed 150°C during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)





Note 3: $V_{DD} = 24~V,~T_{Ch} = 25^{\circ}C$ (initial), L = 1 mH, R_G = 1 $\Omega,~I_{AR} = 2.2A$

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: * Weekly code: (Three digits)

Week of manufacture
(01 for first week of the year, continuing up to 52 or 53)

Year of manufacture
(The last digit of the calendar year)



Gate-source charge 1

Gate switch charge

Gate-drain ("Miller") charge

Electrical Characteristics (Ta = 25°C) www.DataSheet4U.com

| Characteristic | | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--|--------------------|-----------------------|--|-----------|------|-----|------|
| Gate leakage cur | te leakage current | | $V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$ | _ | _ | ±10 | μА |
| Drain cutoff curre | ent | I _{DSS} | V _{DS} = 100 V, V _{GS} = 0 V | _ | _ | 10 | μА |
| Drain-source breakdown voltage | | V _{(BR) DSS} | I _D = 10 mA, V _{GS} = 0 V | 100 | _ | _ | V |
| Diam-source brea | akdown vollage | V _{(BR) DSX} | $I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$ | 60 — — | | V | |
| Gate threshold vo | oltage | V _{th} | V _{DS} = 10 V, I _D = 1 mA | 1.1 | _ | 2.3 | V |
| Dunin navuna ON | un sintan an | _ | V _{GS} = 4.5 V, I _D = 1.1 A | _ | 140 | 190 | m0 |
| Drain-source ON | -resistance | R _{DS} (ON) | V _{GS} = 10 V, I _D = 1.1 A | — 130 180 | | 180 | mΩ |
| Forward transfer | admittance | Y _{fs} | V _{DS} = 10 V, I _D = 1.1 A | 2.7 | 5.4 | _ | S |
| Input capacitance | | C _{iss} | V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz | _ | 360 | _ | pF |
| Reverse transfer capacitance | | C _{rss} | | _ | 22 | _ | |
| Output capacitance | | Coss | | _ | 75 | _ | |
| Reverse transfer capacitance C_{rss} $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ $-$ 22 $-$ 75 $-$ 75 $-$ 8 $-$ 7 $-$ 7 $-$ 14 Switching time | Rise time | t _r | 10 V □ lp = 1 1 A | _ | 7 | _ | |
| | _ | | | | | | |
| Switching time | Fall time | t _f | 4.7 D | _ | 3 | _ | ns |
| | Turn-off time | t _{off} | V _{DD} ≃ 50 V Duty ≦ 1%, t _W = 10 μs | _ | 17 | _ | |
| Total gate charge (gate-source plus gate-drain) | | 0 | $V_{DD} \simeq 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2.2 \text{ A}$ | _ | 7.5 | _ | |
| | | Qg | $V_{DD} \simeq 80 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 2.2 \text{ A}$ | _ | 4.5 | _ | 1 |
| | | | | | | | 4 |

Source-Drain Ratings and Characteristics (Ta = 25°C)

 Q_{gs1}

 Q_{gd}

 Q_{SW}

| Character | istic | | Symbol | Test Condition | Min | Тур. | Max | Unit |
|-------------------------|-------|----------|------------------|--|-----|------|------|------|
| Drain reverse current | Pulse | (Note 1) | I _{DRP} | _ | _ | _ | 8.8 | Α |
| Forward voltage (diode) | | | V _{DSF} | I _{DR} = 2.2 A, V _{GS} = 0 V | _ | _ | -1.2 | ٧ |

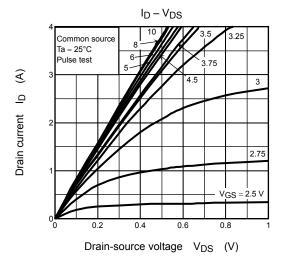
 $V_{DD} \simeq 80~V,~V_{GS} = 10~V,~I_D = 2.2~A$

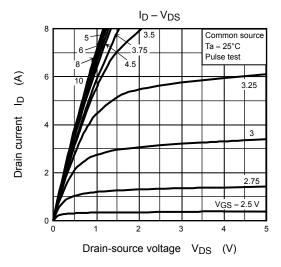
1.6

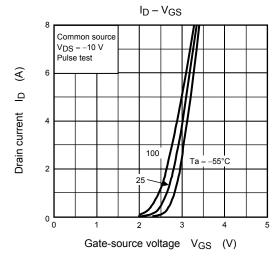
1.3

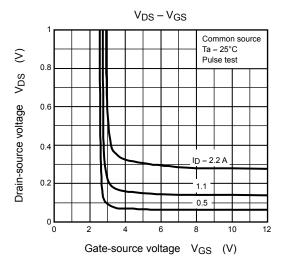
2.0

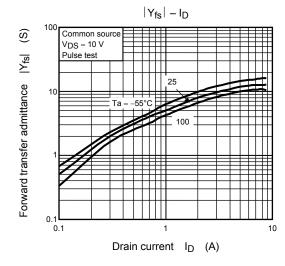
nC

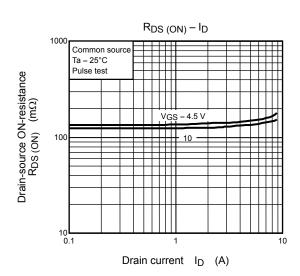


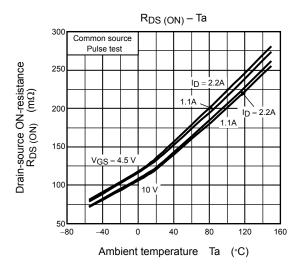


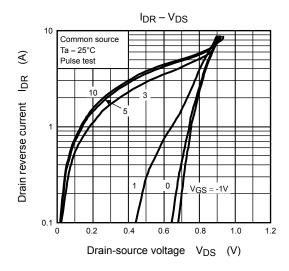


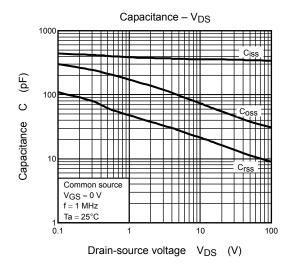


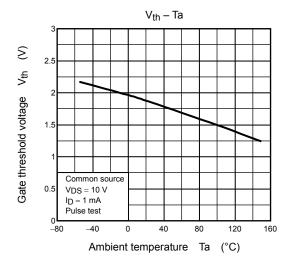


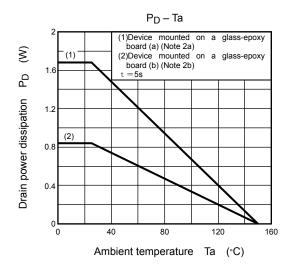


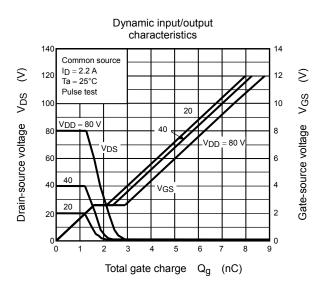


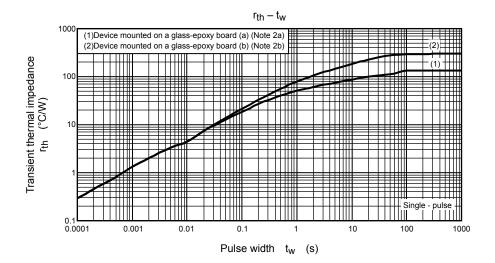


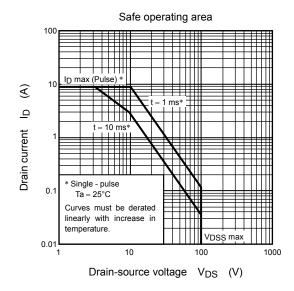












TPCP8003-H

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